

Publikationen

(2006): Intermittent contact scanning capacitance microscopy - An improved method for 2D doping profiling. In: Nanotech Northern Europe, Helsinki, Finnland.

(2005): Intermittent Contact Scanning Capacitance Microscopy-First Results. In: Workshop on Scanning Probe Microscopy and Related Techniques, Villach, Österreich.

(2005): Intermittent contact scanning capacitance microscopy-A novel method for 2D doping profiling. In: 16th European Symposium on Reliability of Electron Devices, Failure Physics and Analysis (ESREF), Arcachon, Frankreich.

(2005): Intermittent contact scanning capacitance microscopy-A novel method for 2D doping profiling. In: Microelectronics Reliability, vol. 45, pp. 1568-1571.